
**Elektromagnetna združljivost (EMC) – 4-11. del: Preskusne in merilne tehnike –
Preskusi odpornosti proti upadom napetosti, kratkotrajnim prekinitvam in
napetostnim kolebanjem (IEC 61000-4-11:2004)**

Electromagnetic compatibility (EMC) - Part 4-11: Testing and measurement
techniques - Voltage dips, short interruptions and voltage variations immunity tests
(IEC 61000-4-11:2004)

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**Electromagnetic compatibility (EMC)
Part 4-11: Testing and measurement techniques -
Voltage dips, short interruptions and voltage variations immunity tests
(IEC 61000-4-11:2004)**

Compatibilité électromagnétique (CEM)
Partie 4-11: Techniques d'essai
et de mesure -
Essais d'immunité aux creux de tension,
coupures brèves et variations de tension
(CEI 61000-4-11:2004)

Elektromagnetische Verträglichkeit (EMV)
Teil 4-11: Prüf- und Messverfahren -
Prüfungen der Störfestigkeit
gegen Spannungseinbrüche,
Kurzzeitunterbrechungen
und Spannungsschwankungen
(IEC 61000-4-11:2004)

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Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

CENELEC members are the national electrotechnical committees of Austria, Belgium, Cyprus, Czech Republic, Denmark, Estonia, Finland, France, Germany, Greece, Hungary, Iceland, Ireland, Italy, Latvia, Lithuania, Luxembourg, Malta, Netherlands, Norway, Poland, Portugal, Slovakia, Slovenia, Spain, Sweden, Switzerland and United Kingdom.

CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

Foreword

The text of document 77A/452/FDIS, future edition 2 of IEC 61000-4-11, prepared by SC 77A, Low frequency phenomena, of IEC TC 77, Electromagnetic compatibility, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 61000-4-11 on 2004-06-01.

This European Standard replaces EN 61000-4-11:1994 + A1:2001.

It constitutes a technical revision in which

- 1) preferred test values and durations have been added for the different environment classes;
- 2) the tests for the three-phase systems have been specified.

The following dates were fixed:

- latest date by which the EN has to be implemented
at national level by publication of an identical
national standard or by endorsement (dop) 2005-03-01
- latest date by which the national standards conflicting
with the EN have to be withdrawn (dow) 2007-06-01

Annex ZA has been added by CENELEC.

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The text of the International Standard IEC 61000-4-11:2004 was approved by CENELEC as a European Standard without any modification.

In the official version, for Bibliography, the following notes have to be added for the standards indicated:

IEC 61000-2-4	NOTE	Harmonized as EN 61000-2-4:2002 (not modified).
IEC 61000-4-14	NOTE	Harmonized as EN 61000-4-14:1999 (not modified).

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE Where an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC/TR 61000-2-8	- ¹⁾	Electromagnetic compatibility (EMC) Part 2-8: Environment - Voltage dips and short interruptions on public electric power supply systems with statistical measurement results	-	-

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¹⁾ Undated reference.

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INTERNATIONAL STANDARD

IEC
61000-4-11

Second edition
2004-03

BASIC EMC PUBLICATION

Electromagnetic compatibility (EMC) –

Part 4-11: Testing and measurement techniques – Voltage dips, short interruptions and voltage variations immunity tests

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

ELECTROMAGNETIC COMPATIBILITY (EMC) –**Part 4-11: Testing and measurement techniques –
Voltage dips, short interruptions and
voltage variations immunity tests**

FOREWORD

- 1) The International Electrotechnical Commission (IEC) is a worldwide organization for standardization comprising all national electrotechnical committees (IEC National Committees). The object of IEC is to promote international co-operation on all questions concerning standardization in the electrical and electronic fields. To this end and in addition to other activities, IEC publishes International Standards, Technical Specifications, Technical Reports, Publicly Available Specifications (PAS) and Guides (hereafter referred to as "IEC Publication(s)"). Their preparation is entrusted to technical committees; any IEC National Committee interested in the subject dealt with may participate in this preparatory work. International, governmental and non-governmental organizations liaising with the IEC also participate in this preparation. IEC collaborates closely with the International Organization for Standardization (ISO) in accordance with conditions determined by agreement between the two organizations.
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International Standard IEC 61000-4-11 has been prepared by subcommittee 77A: Low frequency phenomena, of IEC technical committee 77: Electromagnetic compatibility.

This second edition cancels and replaces the first edition published in 1994 and its amendment 1 (2000). This second edition constitutes a technical revision in which

- 1) preferred test values and durations have been added for the different environment classes;
- 2) the tests for the three-phase systems have been specified.

It forms part 4-11 of IEC 61000. It has the status of a Basic EMC Publication in accordance with IEC Guide 107.

The text of this standard is based on the following documents:

FDIS	Report on voting
77A/452/FDIS	77A/455/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

The committee has decided that the contents of this publication will remain unchanged until 2008. At this date, the publication will be

- reconfirmed;
- withdrawn;
- replaced by a revised edition, or
- amended.

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INTRODUCTION

IEC 61000 is published in separate parts according to the following structure:

Part 1: General

General considerations (introduction, fundamental principles)

Definitions, terminology

Part 2: Environment

Description of the environment

Classification of the environment

Compatibility levels

Part 3: Limits

Emission limits

Immunity limits (in so far as they do not fall under the responsibility of the product committees)

Part 4: Testing and measurement techniques

Measurement techniques

Testing techniques

Part 5: Installation and mitigation guidelines

Installation guidelines

Mitigation methods and devices

[SIST EN 61000-4-11:2005](https://standards.iteh.ai/catalog/standards/sist/1cec2b01-b09e-4abf-a562-9a5d637b81f7/sist-en-61000-4-11-2005)

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Part 6: Generic standards

Part 9: Miscellaneous

Each part is further subdivided into several parts, published either as International Standards or as technical specifications or technical reports, some of which have already been published as sections. Others will be published with the part number followed by a dash and a second number identifying the subdivision (example: 61000-6-1).

ELECTROMAGNETIC COMPATIBILITY (EMC) –

Part 4-11: Testing and measurement techniques – Voltage dips, short interruptions and voltage variations immunity tests

1 Scope

This part of IEC 61000 defines the immunity test methods and range of preferred test levels for electrical and electronic equipment connected to low-voltage power supply networks for voltage dips, short interruptions, and voltage variations.

This standard applies to electrical and electronic equipment having a rated input current not exceeding 16 A per phase, for connection to 50 Hz or 60 Hz a.c. networks.

It does not apply to electrical and electronic equipment for connection to 400 Hz a.c. networks. Tests for these networks will be covered by future IEC standards.

The object of this standard is to establish a common reference for evaluating the immunity of electrical and electronic equipment when subjected to voltage dips, short interruptions and voltage variations.

NOTE Voltage fluctuation immunity tests are covered by IEC 61000-4-14.

The test method documented in this part of IEC 61000 describes a consistent method to assess the immunity of equipment or a system against a defined phenomenon. As described in IEC Guide 107, this is a basic EMC publication for use by product committees of the IEC. As also stated in Guide 107, the IEC product committees are responsible for determining whether this immunity test standard should be applied or not, and, if applied, they are responsible for defining the appropriate test levels. Technical committee 77 and its sub-committees are prepared to co-operate with product committees in the evaluation of the value of particular immunity tests for their products.

2 Normative references

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 61000-2-8, *Electromagnetic compatibility (EMC) – Part 2-8: Environment – Voltage dips and short interruptions on public electric power supply systems with statistical measurement results*

3 Terms and definitions

For the purpose of this document, the following terms and definitions apply: